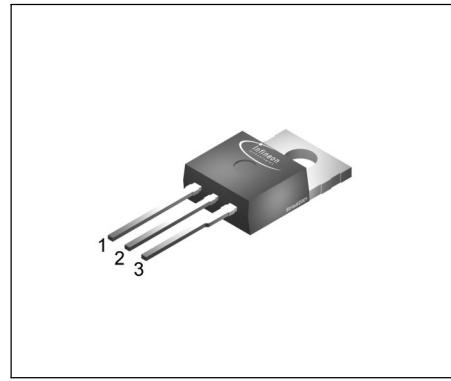


SIPMOS® Power Transistor
BUZ 73A H

- N channel
- Enhancement mode
- Avalanche-rated
- Pb-free lead plating; RoHS compliant
- . Halogen-free according to IEC61249-2-21



Halogen-Free

Pin 1	Pin 2	Pin 3
G	D	S

Type	V_{DS}	I_D	$R_{DS(on)}$	Package	Pb-free
BUZ 73 A	200 V	5.5 A	0.6 Ω	PG-T0-220-3	yes

Maximum Ratings

Parameter	Symbol	Values	Unit
Continuous drain current	I_D	5.5	A
$T_C = 37^\circ\text{C}$			
Pulsed drain current	$I_{D\text{puls}}$	22	
$T_C = 25^\circ\text{C}$			
Avalanche current, limited by $T_{j\text{max}}$	I_{AR}	7	
Avalanche energy, periodic limited by $T_{j\text{max}}$	E_{AR}	6.5	mJ
Avalanche energy, single pulse	E_{AS}		
$I_D = 7 \text{ A}, V_{DD} = 50 \text{ V}, R_{GS} = 25 \Omega$			
$L = 3.67 \text{ mH}, T_j = 25^\circ\text{C}$		120	
Gate source voltage	V_{GS}	± 20	V
Power dissipation	P_{tot}		W
$T_C = 25^\circ\text{C}$		40	
Operating temperature	T_j	-55 ... + 150	°C
Storage temperature	T_{stg}	-55 ... + 150	
Thermal resistance, chip case	R_{thJC}	≤ 3.1	K/W
Thermal resistance, chip to ambient	R_{thJA}	75	
DIN humidity category, DIN 40 040		E	
IEC climatic category, DIN IEC 68-1		55 / 150 / 56	

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Static Characteristics

Drain- source breakdown voltage $V_{GS} = 0 \text{ V}, I_D = 0.25 \text{ mA}, T_j = 25^\circ\text{C}$	$V_{(\text{BR})\text{DSS}}$	200	-	-	V
Gate threshold voltage $V_{GS} = V_{DS}, I_D = 1 \text{ mA}$	$V_{GS(\text{th})}$	2.1	3	4	
Zero gate voltage drain current $V_{DS} = 200 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 25^\circ\text{C}$ $V_{DS} = 200 \text{ V}, V_{GS} = 0 \text{ V}, T_j = 125^\circ\text{C}$	I_{DSS}	-	0.1	1	μA
Gate-source leakage current $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	I_{GSS}	-	10	100	nA
Drain-Source on-resistance $V_{GS} = 10 \text{ V}, I_D = 4.5 \text{ A}$	$R_{\text{DS}(\text{on})}$	-	0.5	0.6	Ω

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Dynamic Characteristics

Transconductance $V_{DS} \geq 2 * I_D * R_{DS(on)max}$, $I_D = 4.5 \text{ A}$	g_{fs}	3	4.2	-	S
Input capacitance $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1 \text{ MHz}$	C_{iss}	-	400	530	pF
Output capacitance $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1 \text{ MHz}$	C_{oss}	-	85	130	
Reverse transfer capacitance $V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1 \text{ MHz}$	C_{rss}	-	45	70	
Turn-on delay time $V_{DD} = 30 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 3 \text{ A}$ $R_{GS} = 50 \Omega$	$t_{d(on)}$	-	10	15	ns
Rise time $V_{DD} = 30 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 3 \text{ A}$ $R_{GS} = 50 \Omega$	t_r	-	40	60	
Turn-off delay time $V_{DD} = 30 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 3 \text{ A}$ $R_{GS} = 50 \Omega$	$t_{d(off)}$	-	55	75	
Fall time $V_{DD} = 30 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 3 \text{ A}$ $R_{GS} = 50 \Omega$	t_f	-	30	40	

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

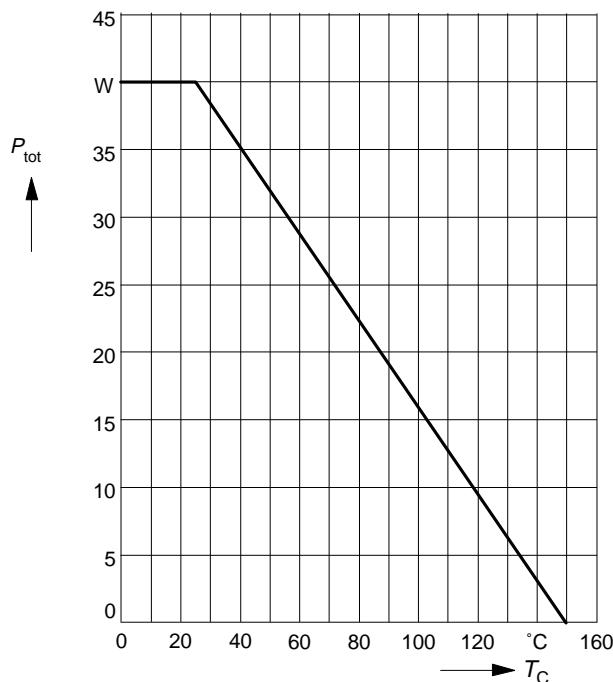
Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Reverse Diode

Inverse diode continuous forward current $T_C = 25^\circ\text{C}$	I_S	-	-	5.5	A
Inverse diode direct current,pulsed $T_C = 25^\circ\text{C}$	I_{SM}	-	-	22	
Inverse diode forward voltage $V_{GS} = 0 \text{ V}, I_F = 14 \text{ A}$	V_{SD}	-	1.3	1.7	V
Reverse recovery time $V_R = 100 \text{ V}, I_F=I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	t_{rr}	-	200	-	ns
Reverse recovery charge $V_R = 100 \text{ V}, I_F=I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$	Q_{rr}	-	0.6	-	μC

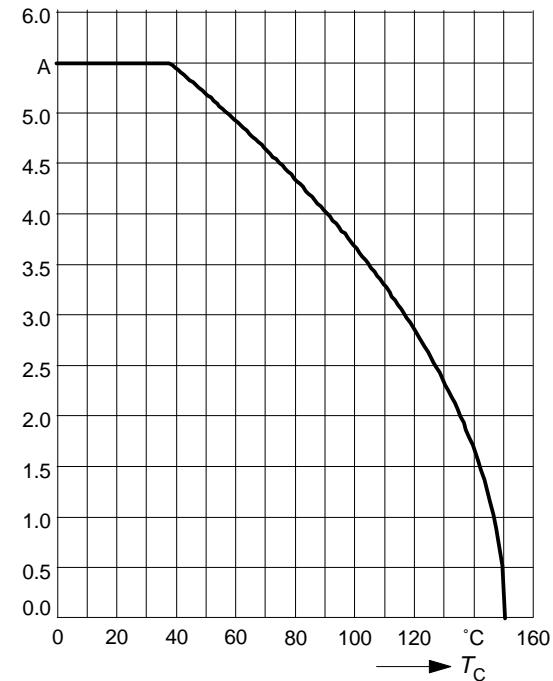
Power dissipation

$$P_{\text{tot}} = f(T_C)$$


Drain current

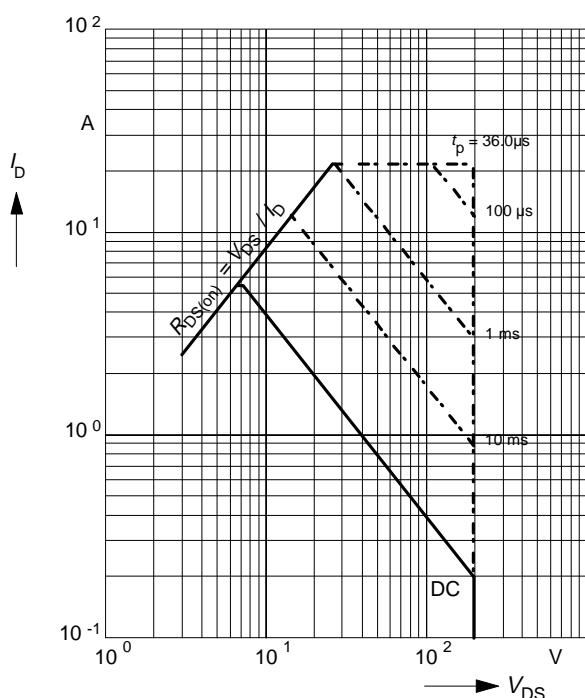
$$I_D = f(T_C)$$

parameter: $V_{GS} \geq 10 \text{ V}$


Safe operating area

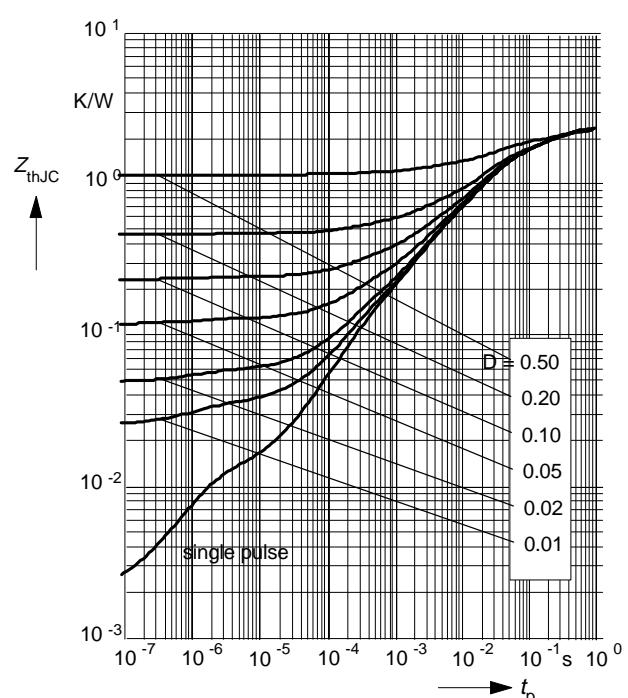
$$I_D = f(V_{DS})$$

parameter: $D = 0.01$, $T_C = 25^\circ\text{C}$


Transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

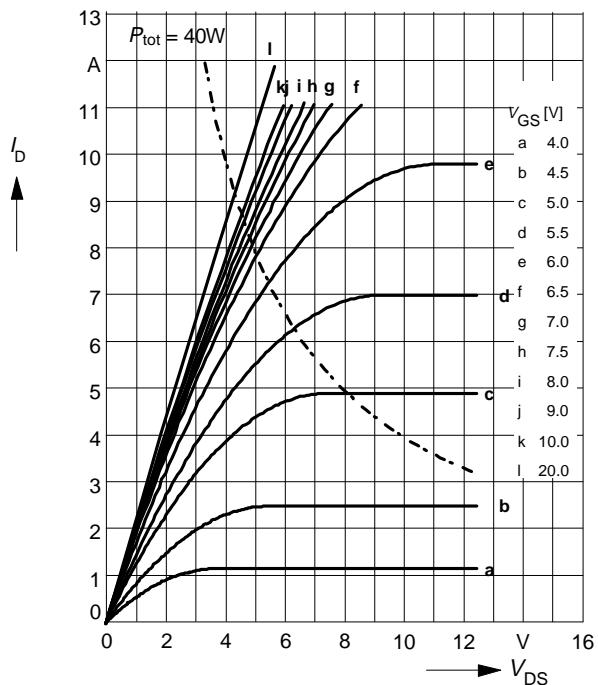
parameter: $D = t_p / T$



Typ. output characteristics

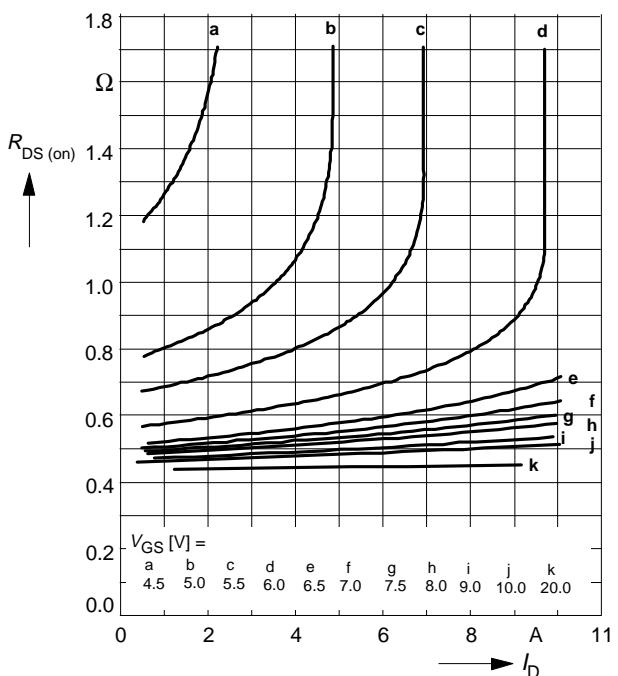
$$I_D = f(V_{DS})$$

parameter: $t_p = 80 \mu s$


Typ. drain-source on-resistance

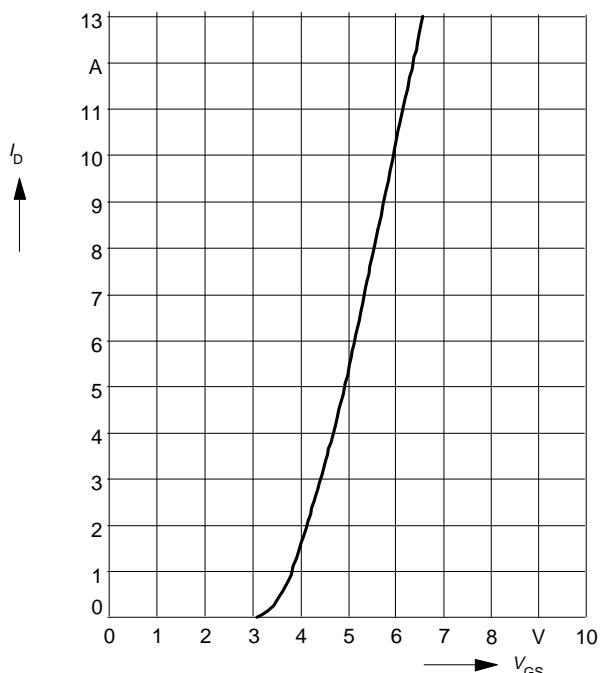
$$R_{DS(on)} = f(I_D)$$

parameter: V_{GS}


Typ. transfer characteristics $I_D = f(V_{GS})$

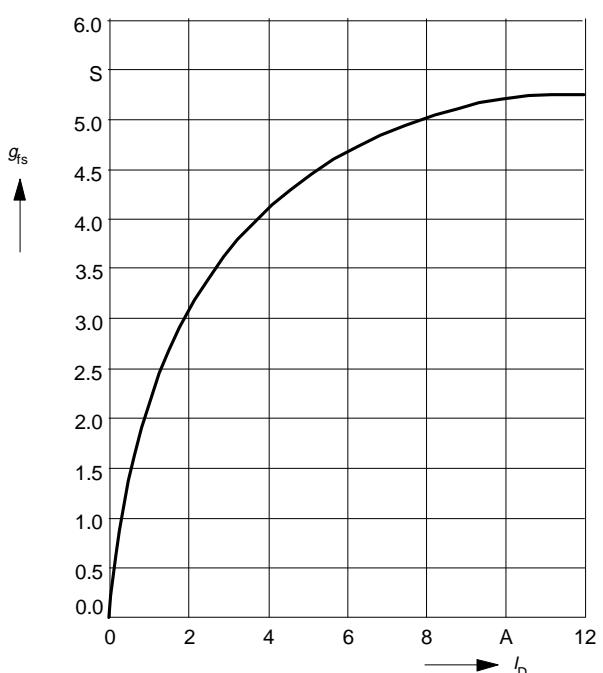
parameter: $t_p = 80 \mu s$

$$V_{DS} \geq 2 \times I_D \times R_{DS(on)\max}$$


Typ. forward transconductance $g_{fs} = f(I_D)$

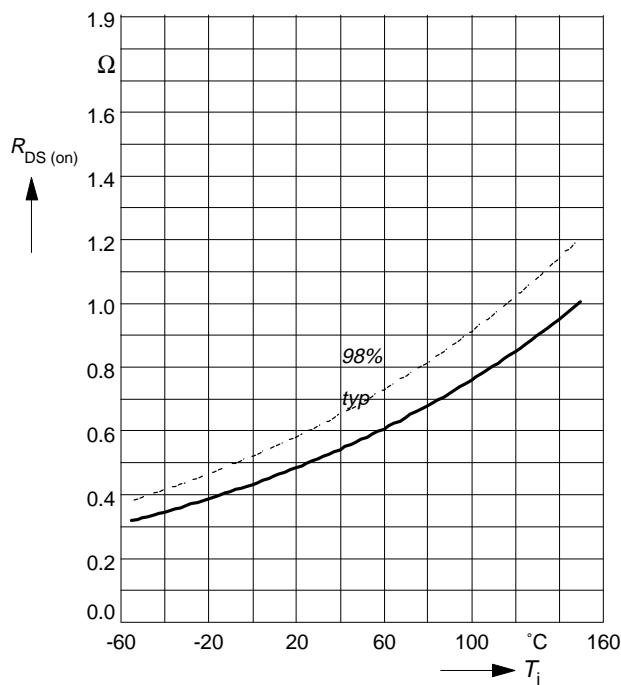
parameter: $t_p = 80 \mu s$,

$$V_{DS} \geq 2 \times I_D \times R_{DS(on)\max}$$



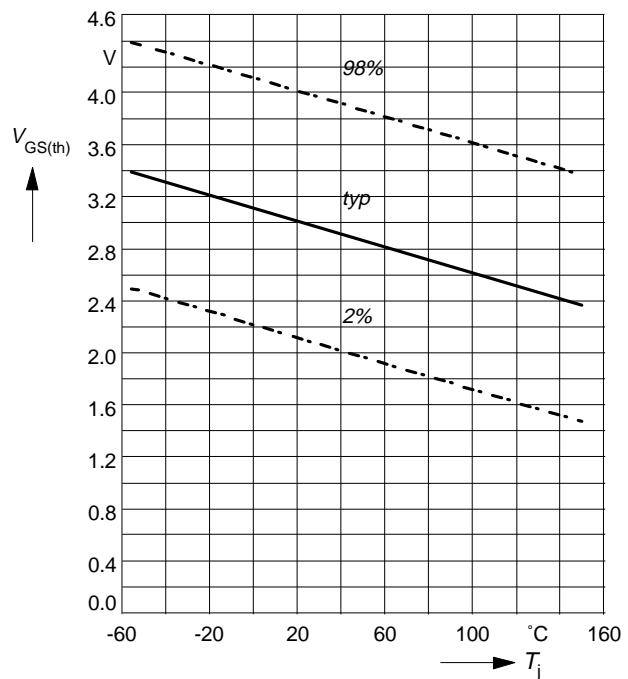
Drain-source on-resistance

$R_{DS(on)} = f(T_j)$
parameter: $I_D = 4.5 \text{ A}$, $V_{GS} = 10 \text{ V}$



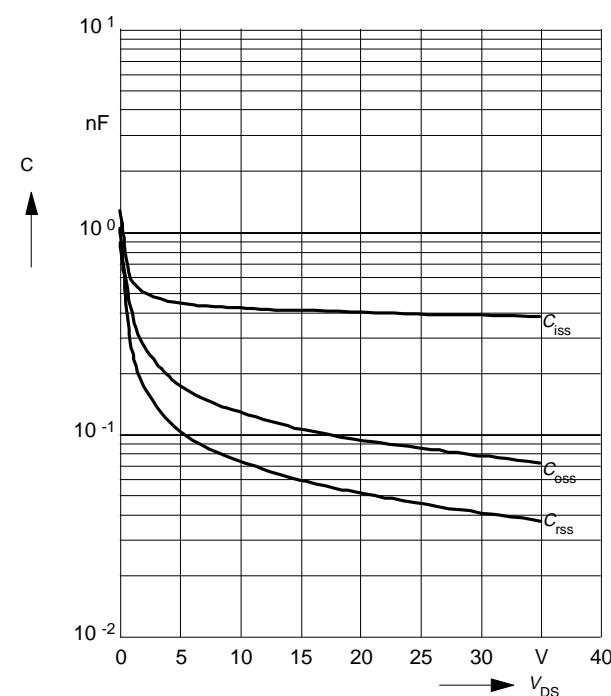
Gate threshold voltage

$V_{GS(th)} = f(T_j)$
parameter: $V_{GS} = V_{DS}$, $I_D = 1 \text{ mA}$



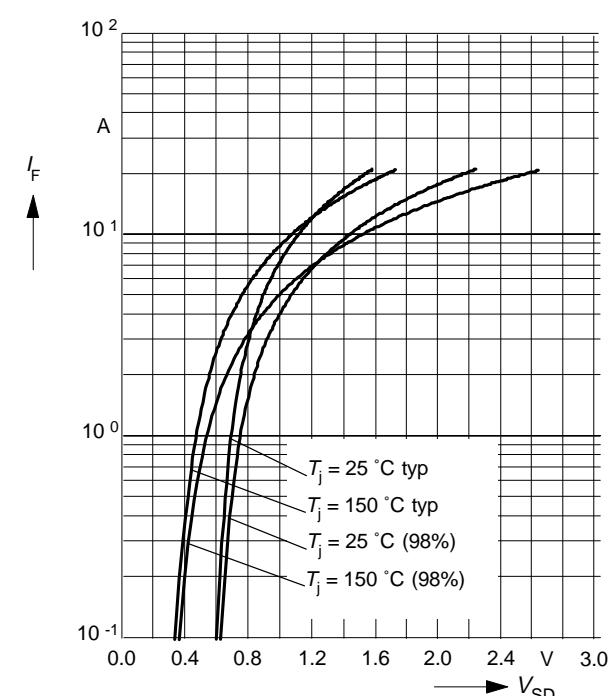
Typ. capacitances

$C = f(V_{DS})$
parameter: $V_{GS} = 0 \text{ V}$, $f = 1 \text{ MHz}$



Forward characteristics of reverse diode

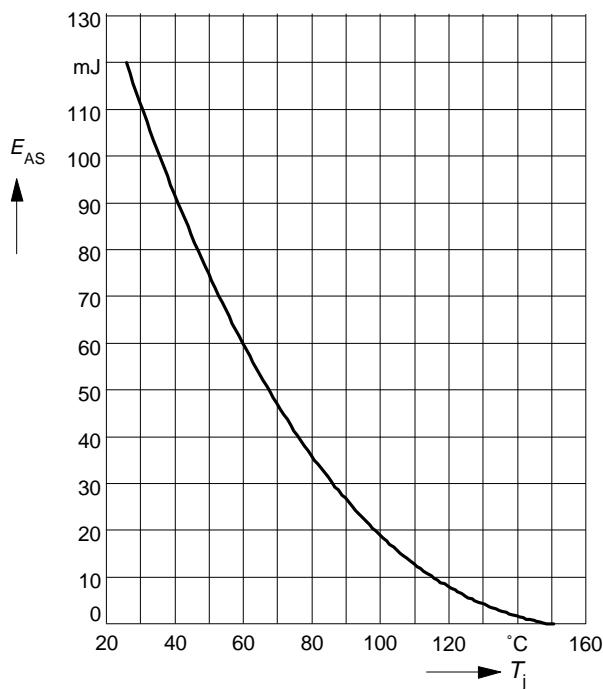
$I_F = f(V_{SD})$
parameter: T_j , $t_p = 80 \mu\text{s}$



Avalanche energy $E_{AS} = f(T_j)$

parameter: $I_D = 7 \text{ A}$, $V_{DD} = 50 \text{ V}$

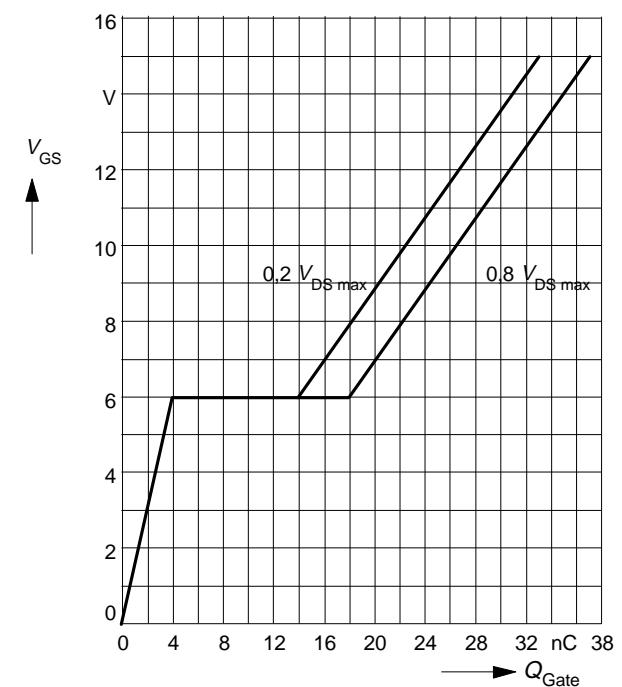
$R_{GS} = 25 \Omega$, $L = 3.67 \text{ mH}$



Typ. gate charge

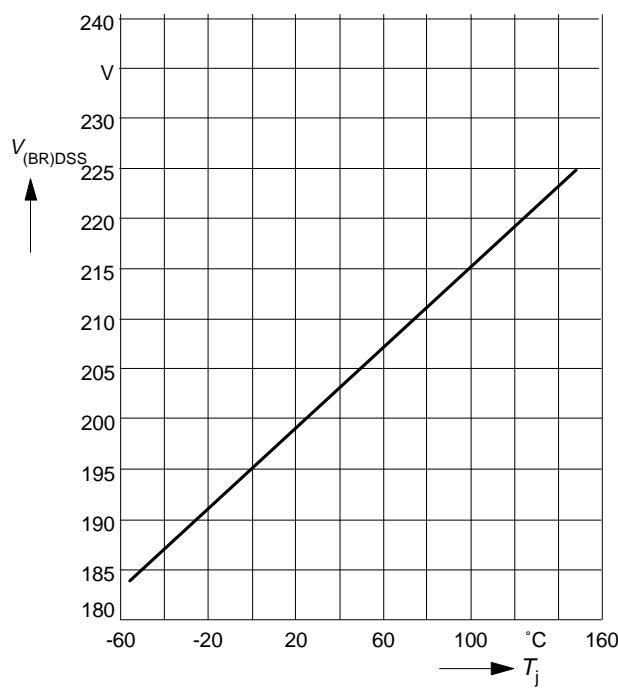
$V_{GS} = f(Q_{Gate})$

parameter: $I_D \text{ puls} = 14 \text{ A}$

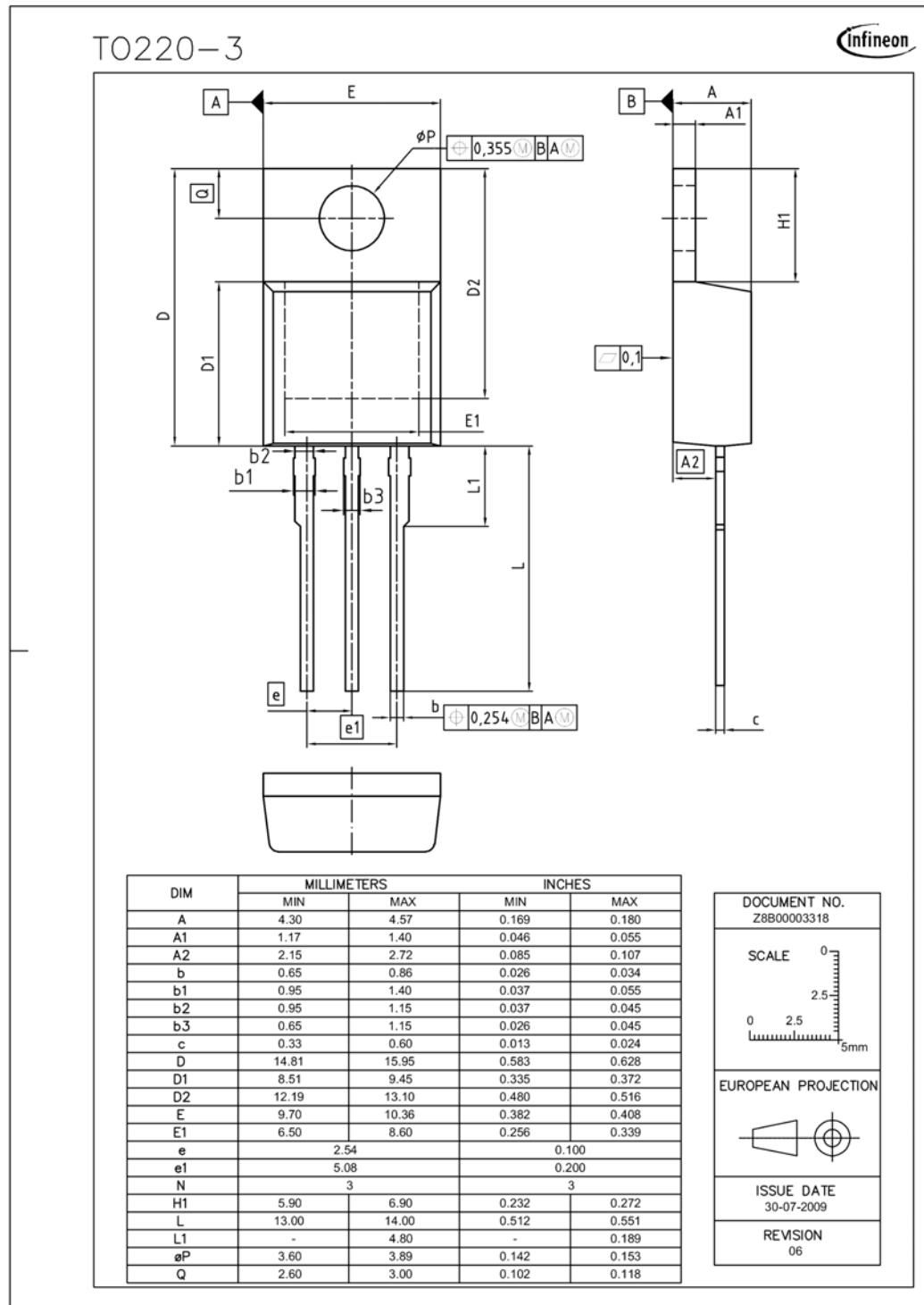


Drain-source breakdown voltage

$V_{(BR)DSS} = f(T_j)$



Package Drawing: TO220-3



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